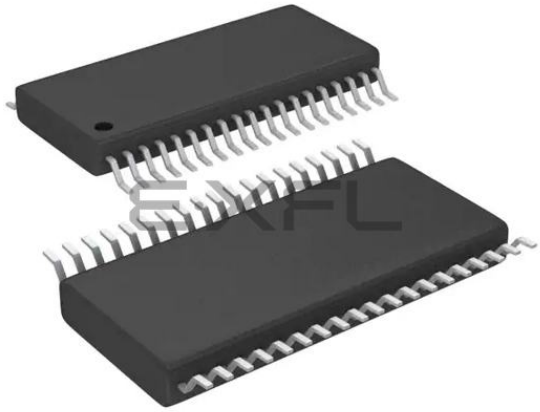

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	27
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1201q040f0016abxuma1

Table 4 XMC1200 Chip Identification Number (cont'd)

Derivative	Value	Marking
XMC1202-T028X0016	00012023 01CF00FF 00001FF7 00008000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1202-T028X0032	00012023 01CF00FF 00001FF7 00008000 00000C00 00001000 00009000 201ED083$_H$	AB
XMC1202-T028X0064	00012023 01CF00FF 00001FF7 00008000 00000C00 00001000 00011000 201ED083$_H$	AB
XMC1202-T016X0016	00012033 01CF00FF 00001FF7 00008000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1202-T016X0032	00012033 01CF00FF 00001FF7 00008000 00000C00 00001000 00009000 201ED083$_H$	AB
XMC1202-T016X0064	00012033 01CF00FF 00001FF7 00008000 00000C00 00001000 00011000 201ED083$_H$	AB
XMC1202-Q024X0016	00012063 01CF00FF 00001FF7 00008000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1202-Q024X0032	00012063 01CF00FF 00001FF7 00008000 00000C00 00001000 00009000 201ED083$_H$	AB
XMC1201-Q040F0016	00012042 01CF00FF 00001FF7 00006000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1201-Q040F0032	00012042 01CF00FF 00001FF7 00006000 00000C00 00001000 00009000 201ED083$_H$	AB
XMC1201-Q040F0064	00012042 01CF00FF 00001FF7 00006000 00000C00 00001000 00011000 201ED083$_H$	AB
XMC1201-Q040F0128	00012042 01CF00FF 00001FF7 00006000 00000C00 00001000 00021000 201ED083$_H$	AB
XMC1201-Q040F0200	00012042 01CF00FF 00001FF7 00006000 00000C00 00001000 00033000 201ED083$_H$	AB
XMC1202-Q040X0016	00012043 01CF00FF 00001FF7 00008000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1202-Q040X0032	00012043 01CF00FF 00001FF7 00008000 00000C00 00001000 00009000 201ED083$_H$	AB

2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

2.1 Logic Symbols

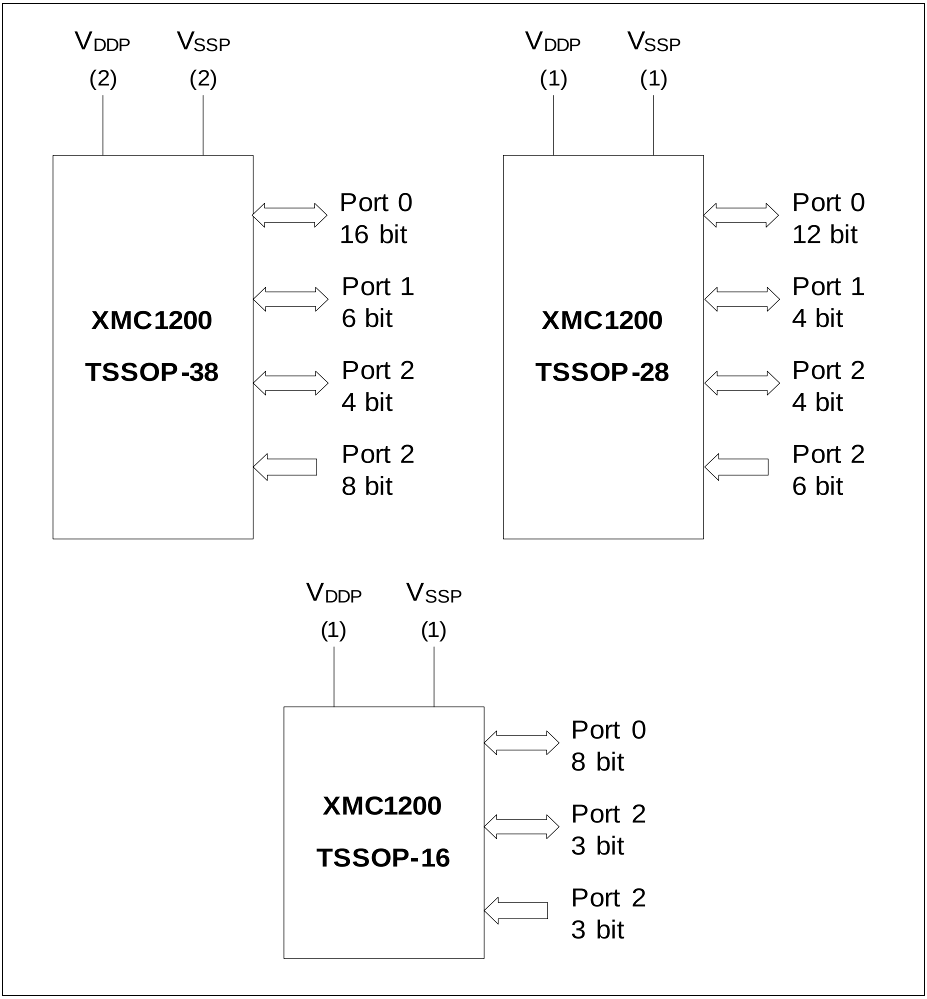

Figure 2 XMC1200 Logic Symbol for TSSOP-38, TSSOP-28 and TSSOP-16

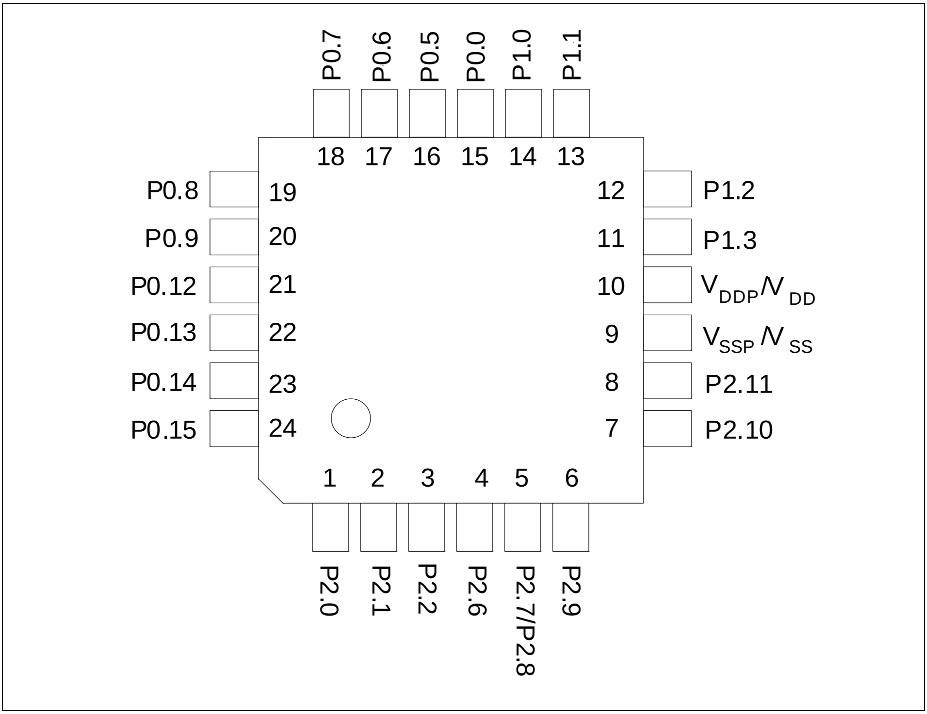

Figure 7 XMC1200 PG-VQFN-24 Pin Configuration (top view)

Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P2.1	2	36	26	2	-	STD_INOUT/AN	
P2.2	3	37	27	3	-	STD_IN/AN	
P2.3	4	38	-	-	-	STD_IN/AN	
P2.4	5	1	-	-	-	STD_IN/AN	
P2.5	6	2	28	-	-	STD_IN/AN	
P2.6	7	3	1	4	16	STD_IN/AN	
P2.7	8	4	2	5	1	STD_IN/AN	
P2.8	9	5	3	5	1	STD_IN/AN	
P2.9	10	6	4	6	2	STD_IN/AN	
P2.10	11	7	5	7	3	STD_INOUT/AN	
P2.11	12	8	6	8	4	STD_INOUT/AN	
VSS	13	9	7	9	5	Power	Supply GND, ADC reference GND
VDD	14	10	8	10	6	Power	Supply VDD, ADC reference voltage/ ORC reference voltage
VDDP	15	10	8	10	6	Power	When VDD is supplied, VDDP has to be supplied with the same voltage.

Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
VSSP	31	25	-	-	-	Power	I/O port ground
VDDP	32	26	-	-	-	Power	I/O port supply
VSSP	Exp. Pad	-	-	Exp. Pad	-	Power	**Exposed Die Pad** The exposed die pad is connected internally to VSSP. For proper operation, it is mandatory to connect the exposed pad to the board ground. For thermal aspects, please refer to the Package and Reliability chapter.

2.2.3 Hardware Controlled I/O Function Description

The following general building block is used to describe the hardware I/O and pull control functions of each PORT pin:

Table 8 Hardware Controlled I/O Function Description

Function	Outputs	Inputs	Pull Control	
	HWO0	HWI0	HW0_PD	HW0_PU
P0.0	MODB.OUT	MODB.INA		
Pn.y			$\overline{\text{MODC.OUT}}$	MODC.OUT

By Pn_HWSEL, it is possible to select between different hardware “masters” (HWO0/HWI0, HWO1/HWI1). The selected peripheral can take control of the pin(s). Hardware control overrules settings in the respective port pin registers. Additional hardware signals HW0_PD/HW1_PD and HW0_PU/HW1_PU controlled by the peripherals can be used to control the pull devices of the pin.

Please refer to the **Hardware Controlled I/O Functions** table for the complete hardware I/O and pull control function mapping.

Table 10 Hardware Controlled I/O Functions

Function	Outputs		Inputs		Pull Control			
	HWO0	HWO1	HWI0	HWI1	HW0_PD	HW0_PU	HW1_PD	HW1_PU
P1.3		USIC0_CH0.DOUT3		USIC0_CH0.HWIN3	$\overline{\text{BCCU0.OUT5}}$	BCCU0.OUT5		
P1.4					$\overline{\text{BCCU0.OUT6}}$	BCCU0.OUT6		
P1.5					$\overline{\text{BCCU0.OUT7}}$	BCCU0.OUT7		
P1.6					$\overline{\text{BCCU0.OUT8}}$	BCCU0.OUT8		
P2.0					$\overline{\text{BCCU0.OUT1}}$	BCCU0.OUT1		
P2.1					$\overline{\text{BCCU0.OUT6}}$	BCCU0.OUT6		
P2.2					$\overline{\text{BCCU0.OUT0}}$	BCCU0.OUT0	$\overline{\text{CCU40.OUT3}}$	CCU40.OUT3
P2.3					$\overline{\text{ACMP2.OUT}}$	ACMP2.OUT		
P2.4					$\overline{\text{BCCU0.OUT8}}$	BCCU0.OUT8		
P2.5					$\overline{\text{ACMP1.OUT}}$	ACMP1.OUT		
P2.6					$\overline{\text{BCCU0.OUT2}}$	BCCU0.OUT2	$\overline{\text{CCU40.OUT3}}$	CCU40.OUT3
P2.7					$\overline{\text{BCCU0.OUT8}}$	BCCU0.OUT8	$\overline{\text{CCU40.OUT3}}$	CCU40.OUT3
P2.8					$\overline{\text{BCCU0.OUT1}}$	BCCU0.OUT1	$\overline{\text{CCU40.OUT2}}$	CCU40.OUT2
P2.9					$\overline{\text{BCCU0.OUT7}}$	BCCU0.OUT7	$\overline{\text{CCU40.OUT2}}$	CCU40.OUT2
P2.10					$\overline{\text{BCCU0.OUT4}}$	BCCU0.OUT4		
P2.11					$\overline{\text{BCCU0.OUT5}}$	BCCU0.OUT5		

If a pin current is outside of the **Operating Conditions** but within the overload conditions, then the parameters of this pin as stated in the Operating Conditions can no longer be guaranteed. Operation is still possible in most cases but with relaxed parameters.

Note: An overload condition on one or more pins does not require a reset.

Note: A series resistor at the pin to limit the current to the maximum permitted overload current is sufficient to handle failure situations like short to battery.

Table 12 Overload Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Input current on any port pin during overload condition	I_{OV}	SR	-5	–	5	mA	
Absolute sum of all input circuit currents during overload condition	I_{OVS}	SR	–	–	25	mA	

Figure 10 shows the path of the input currents during overload via the ESD protection structures. The diodes against V_{DDP} and ground are a simplified representation of these ESD protection structures.

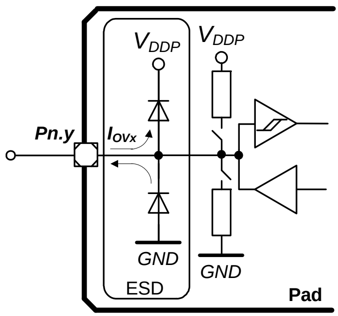

Figure 10 Input Overload Current via ESD structures

Table 13 and **Table 14** list input voltages that can be reached under overload conditions. Note that the absolute maximum input voltages as defined in the **Absolute Maximum Ratings** must not be exceeded during overload.

Table 13 PN-Junction Characterisitics for positive Overload

Pad Type	I_{OV} **= 5 mA,** T_J **= -40 °C**	I_{OV} **= 5 mA,** T_J **= 115 °C**
Standard, High-current, AN/DIG_IN	$V_{IN} = V_{DDP}$ + 0.5 V	$V_{IN} = V_{DDP}$ + 0.5 V

Table 14 PN-Junction Characterisitics for negative Overload

Pad Type	I_{OV} **= 5 mA,** T_J **= -40 °C**	I_{OV} **= 5 mA,** T_J **= 115 °C**
Standard, High-current, AN/DIG_IN	$V_{IN} = V_{SS}$ - 0.5 V	$V_{IN} = V_{SS}$ - 0.5 V

3.1.4 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation and reliability of the XMC1200. All parameters specified in the following tables refer to these operating conditions, unless noted otherwise.

Table 15 Operating Conditions Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Ambient Temperature	T_A SR	-40	–	85	°C	Temp. Range F
		-40	–	105	°C	Temp. Range X
Digital supply voltage[1]	V_{DDP} SR	1.8	–	5.5	V	
MCLK Frequency	f_{MCLK} CC	–	–	33.2	MHz	CPU clock
PCLK Frequency	f_{PCLK} CC	–	–	66.4	MHz	Peripherals clock
Short circuit current of digital outputs	I_{SC} SR	-5	–	5	mA	
Absolute sum of short circuit currents of the device	ΣI_{SC_D} SR	–	–	25	mA	

1) See also the Supply Monitoring thresholds, **Chapter 3.3.2**.

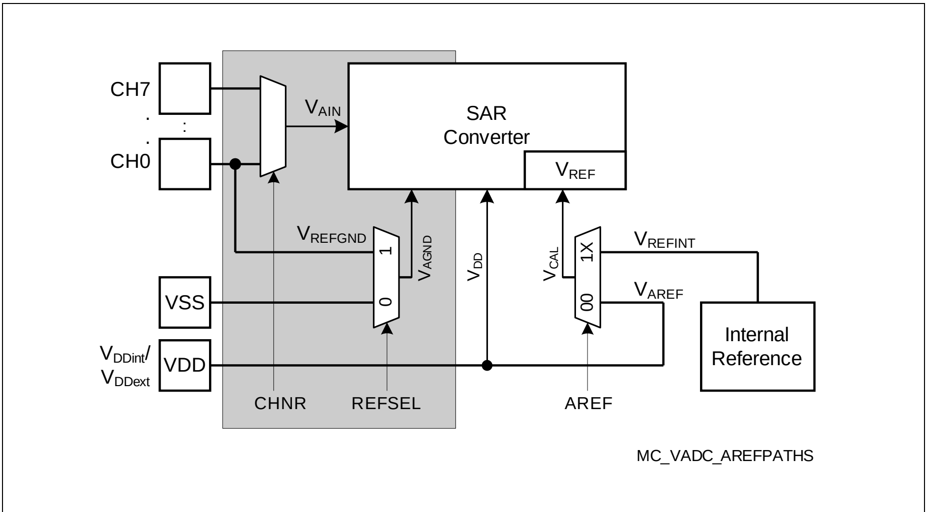

Figure 11 ADC Voltage Supply

3.2.4 Analog Comparator Characteristics

Table 19 below shows the Analog Comparator characteristics.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 19 Analog Comparator Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Notes/ Test Conditions
			Min.	Typ.	Max.		
Input Voltage	V_{CMP}	SR	-0.05	–	V_{DDP} + 0.05	V	
Input Offset	V_{CMPOFF}	CC	–	+/-3	–	mV	High power mode ΔV_{CMP} < 200 mV
			–	+/-20	–	mV	Low power mode ΔV_{CMP} < 200 mV
Propagation Delay[1]	t_{PDELAY}	CC	–	25	–	ns	High power mode, ΔV_{CMP} = 100 mV
			–	80	–	ns	High power mode, ΔV_{CMP} = 25 mV
			–	250	–	ns	Low power mode, ΔV_{CMP} = 100 mV
			–	700	–	ns	Low power mode, ΔV_{CMP} = 25 mV
Current Consumption	I_{ACMP}	CC	–	100	–	µA	First active ACMP in high power mode, ΔV_{CMP} > 30 mV
			–	66	–	µA	Each additional ACMP in high power mode, ΔV_{CMP} > 30 mV
			–	10	–	µA	First active ACMP in low power mode
			–	6	–	µA	Each additional ACMP in low power mode
Input Hysteresis	V_{HYS}	CC	–	+/-15	–	mV	
Filter Delay[1]	t_{FDELAY}	CC	–	5	–	ns	

1) Total Analog Comparator Delay is the sum of Propagation Delay and Filter Delay.

3.2.7 Flash Memory Parameters

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 Flash Memory Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Erase Time per page / sector	t_{ERASE} CC	6.8	7.1	7.6	ms	
Program time per block	t_{PSER} CC	102	152	204	µs	
Wake-Up time	t_{WU} CC	–	32.2	–	µs	
Read time per word	t_a CC	–	50	–	ns	
Data Retention Time	t_{RET} CC	10	–	–	years	Max. 100 erase / program cycles
Flash Wait States [1]	$N_{WSFLASH}$ CC	0	0	0		f_{MCLK} = 8 MHz
		0	1	1		f_{MCLK} = 16 MHz
		1	1.3	2		f_{MCLK} = 32 MHz
Fixed Flash Wait States configured in bit NVM_NVMCONF.WS	$N_{FWSFLASH}$ SR	0	0	1		NVM_CONFIG1. FIXWS = 1_B, $f_{MCLK} \leq$ 16 MHz
		1	1	1		NVM_CONFIG1. FIXWS = 1_B, 16 MHz < f_{MCLK} $\leq$ 32 MHz
Erase Cycles	N_{ECYC} CC	–	–	$5*10^4$	cycles	Sum of page and sector erase cycles
Total Erase Cycles	N_{TECYC} CC	–	–	$2*10^6$	cycles	

1) Flash wait states are automatically inserted by the Flash module during memory read when needed. Typical values are calculated from the execution of the Dhrystone benchmark program.

3.3.4 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 27 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	–	500000	ns	–
SWDCLK low time	t_2 SR	50	–	500000	ns	–
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	–	–	ns	–
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	–	–	ns	–
SWDIO output valid time after SWDCLK rising edge	t_5 CC	–	–	68	ns	C_L = 50 pF
		–	–	62	ns	C_L = 30 pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	–	–	ns	

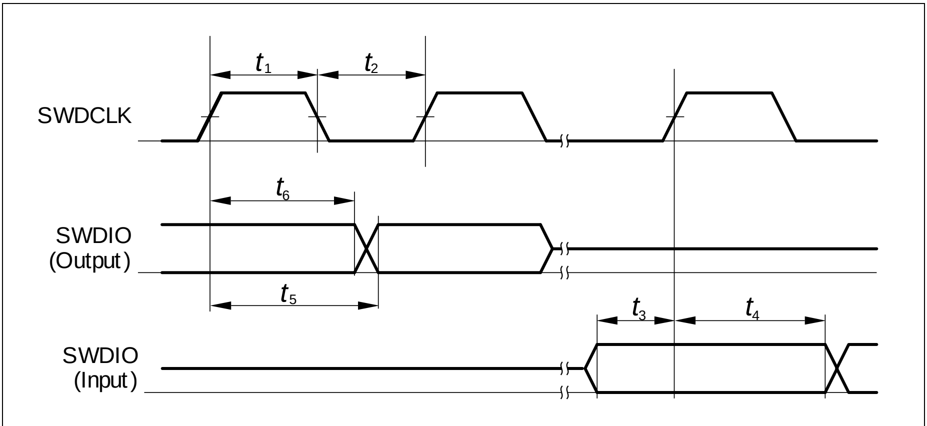

Figure 21 SWD Timing

3.3.5 SPD Timing Requirements

The optimum SPD decision time between 0_B and 1_B is 0.75 µs. With this value the system has maximum robustness against frequency deviations of the sampling clock on tool and on device side. However it is not always possible to exactly match this value with the given constraints for the sample clock. For instance for a oversampling rate of 4, the sample clock will be 8 MHz and in this case the closest possible effective decision time is 5.5 clock cycles (0.69 µs).

Table 28 Optimum Number of Sample Clocks for SPD

Sample Freq.	Sampling Factor	Sample Clocks 0_B	Sample Clocks 1_B	Effective Decision Time[1)]	Remark
8 MHz	4	1 to 5	6 to 12	0.69 µs	The other closest option (0.81 µs) for the effective decision time is less robust.

1) Nominal sample frequency period multiplied with 0.5 + (max. number of 0_B sample clocks)

For a balanced distribution of the timing robustness of SPD between tool and device, the timing requirements for the tool are:

- Frequency deviation of the sample clock is +/- 5%
- Effective decision time is between 0.69 µs and 0.75 µs (calculated with nominal sample frequency)

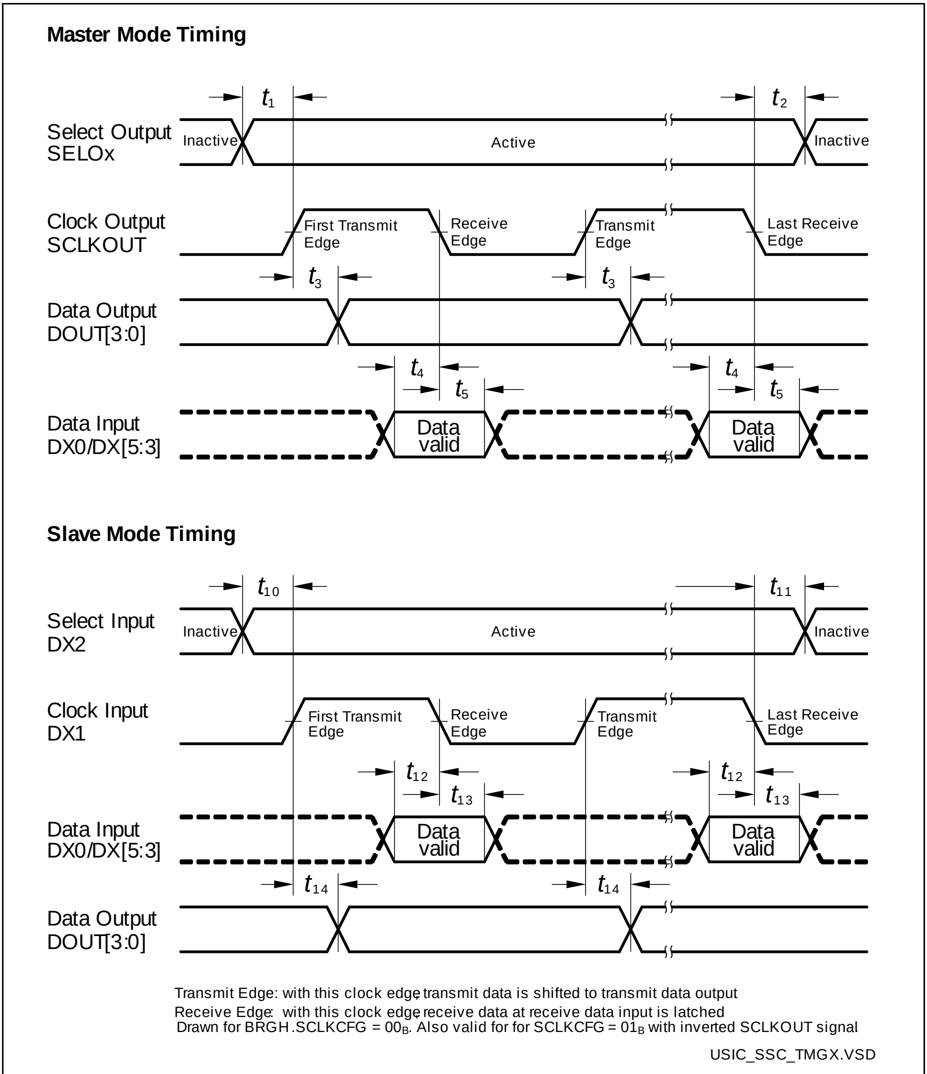

Figure 22 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration, for which the slave select signal is low-active, and the serial clock signal is not shifted and not inverted.

3.3.6.2 Inter-IC (IIC) Interface Timing

The following parameters are applicable for a USIC channel operated in IIC mode.

Note: Operating Conditions apply.

Table 31 USIC IIC Standard Mode Timing[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	-	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	-	-	1000	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	250	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	4.7	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	4.0	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	4.0	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	4.7	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	4.0	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	4.7	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximaley 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

Table 32 USIC IIC Fast Mode Timing[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1*C_b [2)]	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1*C_b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximaley 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

4.2 Package Outlines

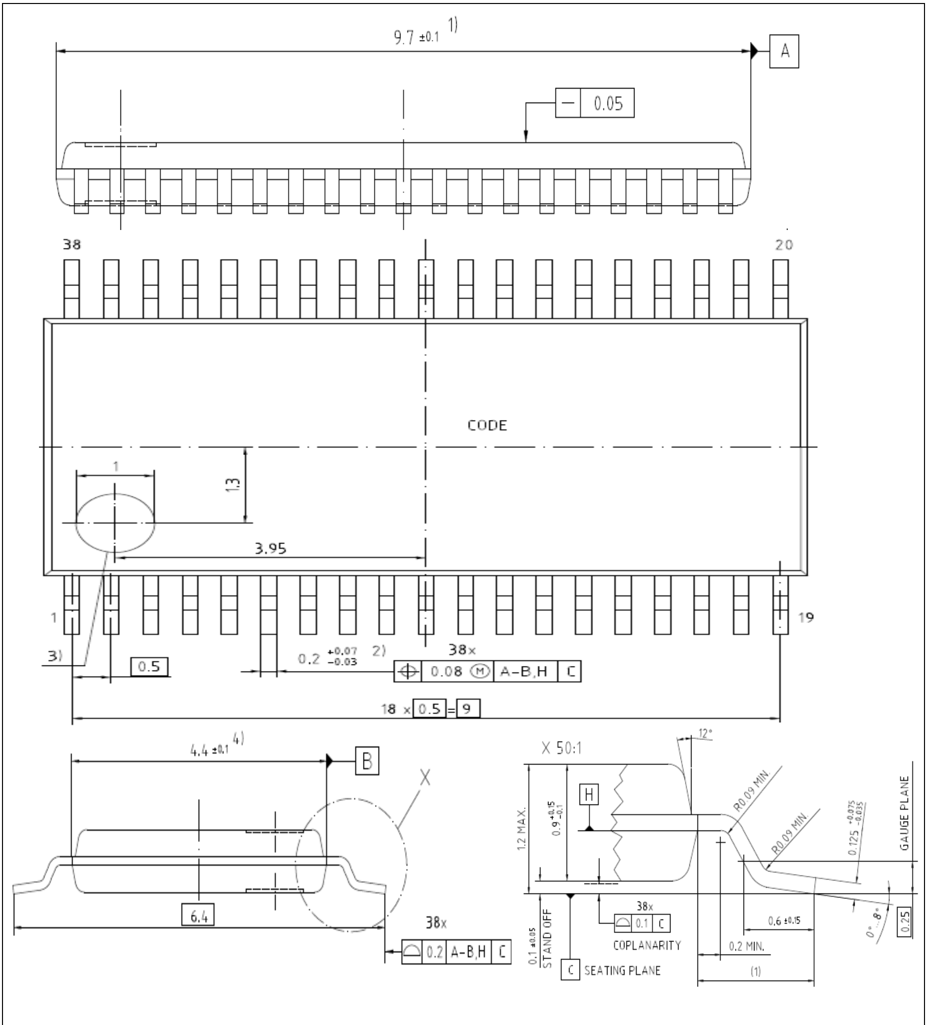

Figure 26 PG-TSSOP-38-9

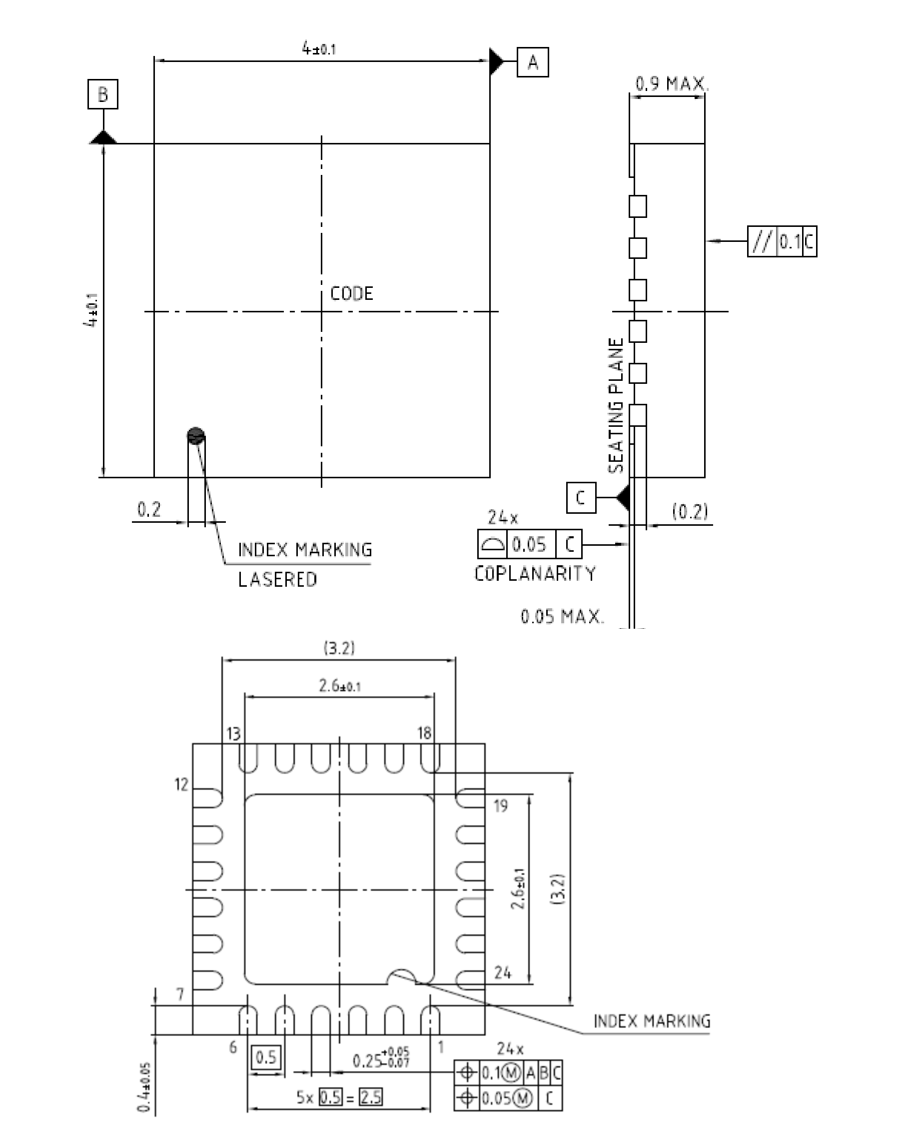

Figure 29 PG-VQFN-24-19